



ALPHA & OMEGA
SEMICONDUCTOR

AOSD62666E
60V Dual N-Channel AlphaSGT™

General Description

- Trench Power AlphaSGT™ technology
- Low $R_{DS(ON)}$
- Logic Level Gate Drive
- ESD Protected
- Excellent Gate Charge x $R_{DS(ON)}$ Product (FOM)
- RoHS and Halogen-Free Compliant

Applications

- Motor Control, Lighting, Industrial and Load switch

Product Summary

V_{DS}	60V
I_D (at $V_{GS}=10V$)	9.5A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 14.5mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$)	< 19mΩ

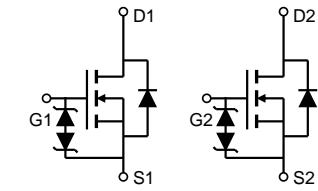
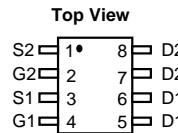
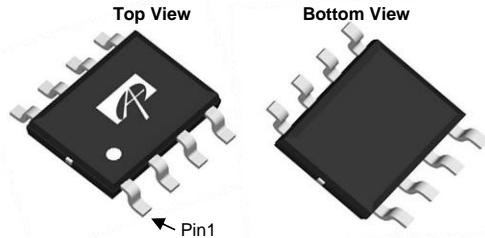
Typical ESD protection

HBM Class 2

100% UIS Tested
100% Rg Tested



SOIC-8



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOSD62666E	SO-8	Tape & Reel	3000

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	9.5	A
$T_A=70^\circ\text{C}$		7.5	
Pulsed Drain Current ^C	I_{DM}	38	
Avalanche Current ^C	I_{AS}	14	A
Avalanche energy $L=0.3\text{mH}$ ^C	E_{AS}	29	mJ
Power Dissipation ^B	P_D	2.5	W
$T_A=25^\circ\text{C}$		1.6	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	42	50	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		70	85	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	30	40	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	60			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=60\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			± 10	μA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.2	1.7	2.2	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=9.5\text{A}$ $T_J=125^\circ\text{C}$		12	14.5	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=8.5\text{A}$		19.2	23.5	
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=9.5\text{A}$		33		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.72	1	V
I_S	Maximum Body-Diode Continuous Current				3.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=30\text{V}, f=1\text{MHz}$		755		pF
C_{oss}	Output Capacitance			220		pF
C_{rss}	Reverse Transfer Capacitance			20		pF
R_g	Gate resistance	$f=1\text{MHz}$	0.6	1.3	2.0	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, I_D=9.5\text{A}$		13.5	20	nC
$Q_g(4.5\text{V})$	Total Gate Charge			6.5	10	nC
Q_{gs}	Gate Source Charge			2.5		nC
Q_{gd}	Gate Drain Charge			3.0		nC
Q_{oss}	Output Charge	$V_{GS}=0\text{V}, V_{DS}=30\text{V}$		11		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, R_L=3.15\Omega, R_{\text{GEN}}=3\Omega$		5		ns
t_r	Turn-On Rise Time			3		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			19		ns
t_f	Turn-Off Fall Time			3		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=9.5\text{A}, di/dt=500\text{A}/\mu\text{s}$		15		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=9.5\text{A}, di/dt=500\text{A}/\mu\text{s}$		45		nC

A. The value of R_{iJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{ C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{ C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{ C}$.

D. The R_{iJA} is the sum of the thermal impedance from junction to lead R_{iUL} and lead to ambient.

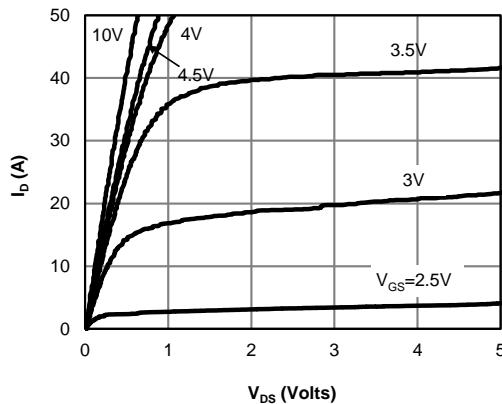
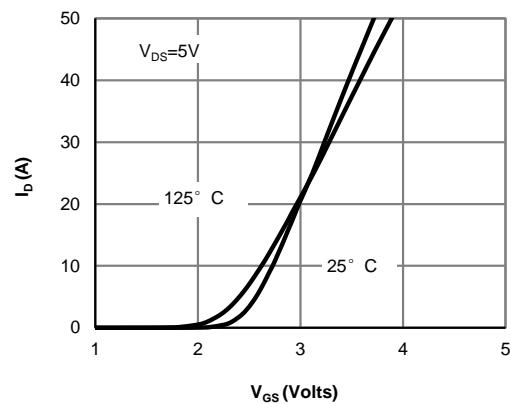
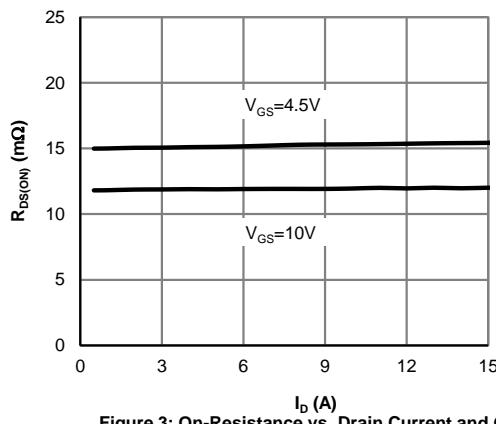
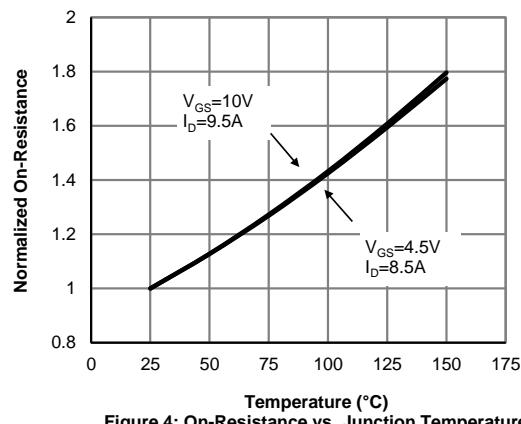
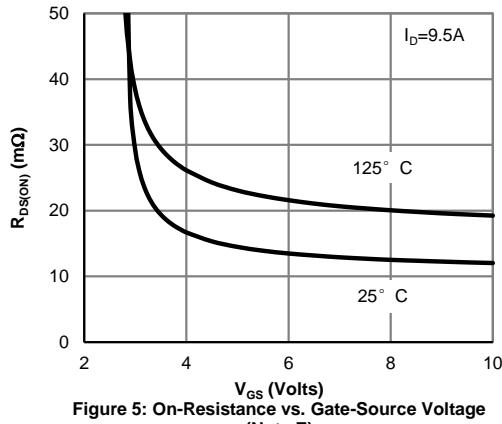
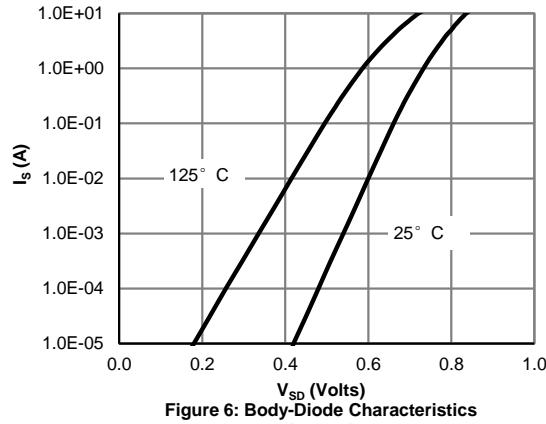
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{ C}$. The SOA curve provides a single pulse rating.

APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO MAKE CHANGES TO PRODUCT SPECIFICATIONS WITHOUT NOTICE. IT IS THE RESPONSIBILITY OF THE CUSTOMER TO EVALUATE SUITABILITY OF THE PRODUCT FOR THEIR INTENDED APPLICATION. CUSTOMER SHALL COMPLY WITH APPLICABLE LEGAL REQUIREMENTS, INCLUDING ALL APPLICABLE EXPORT CONTROL RULES, REGULATIONS AND LIMITATIONS.

AOS' products are provided subject to AOS' terms and conditions of sale which are set forth at:

http://www.aosmd.com/terms_and_conditions_of_sale

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

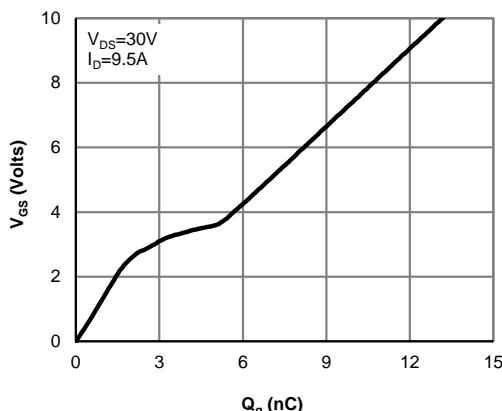
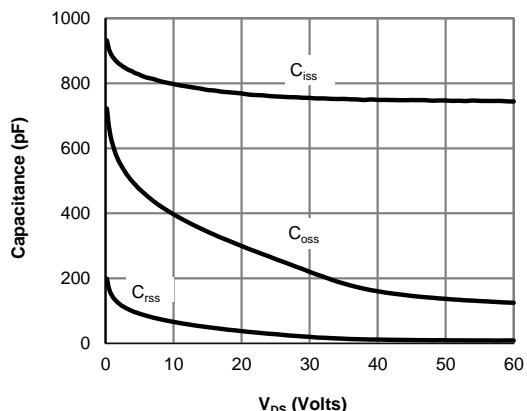
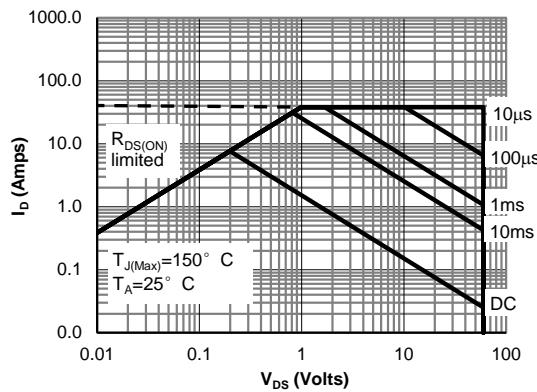
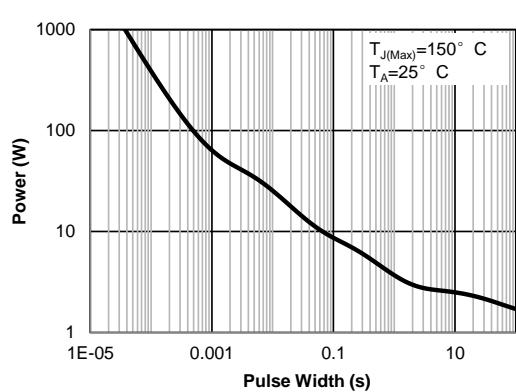
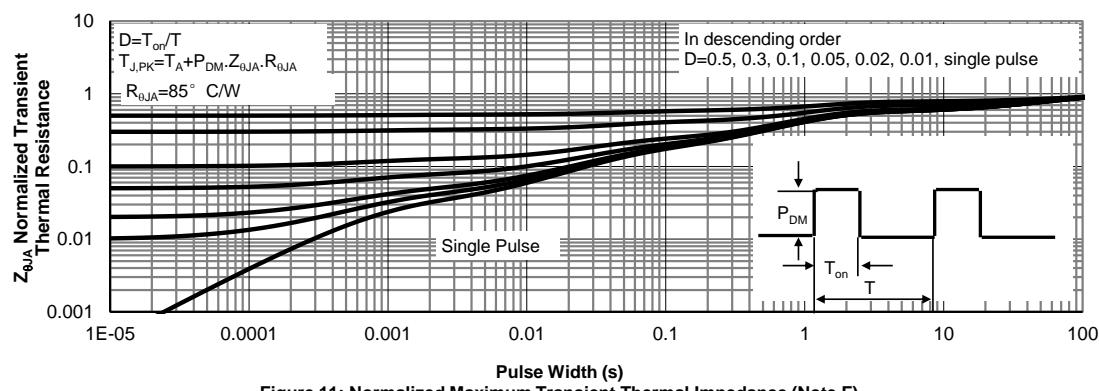
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Figure A: Gate Charge Test Circuit & Waveforms

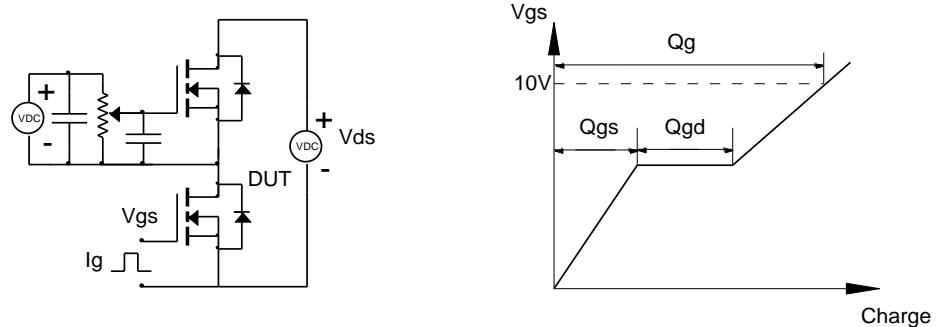


Figure B: Resistive Switching Test Circuit & Waveforms

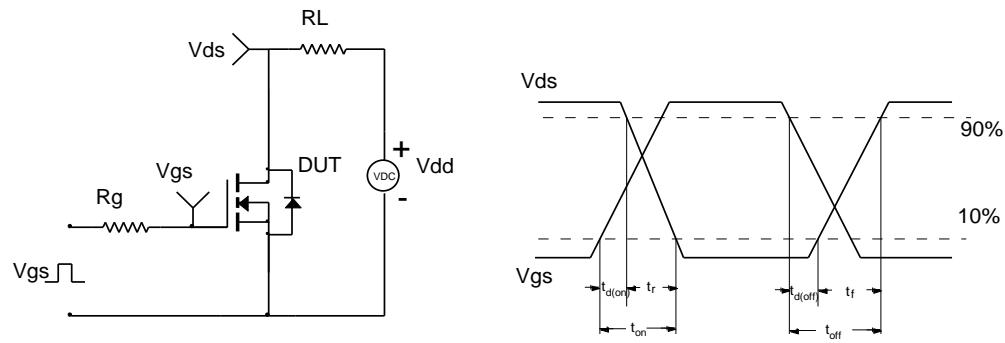


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

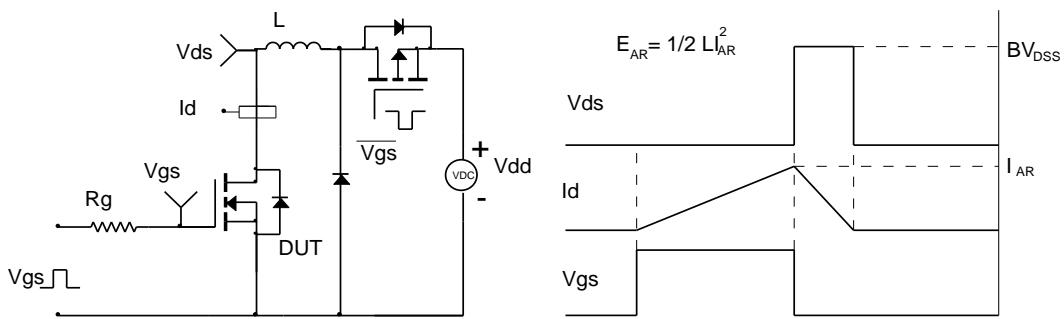


Figure D: Diode Recovery Test Circuit & Waveforms

